

STD35NF06

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STD35NF06	60V	<0.020Ω	35A

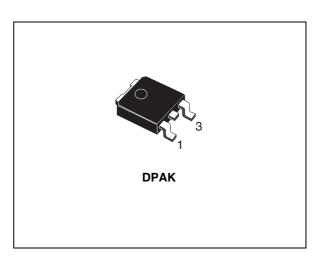
- Exceptional dv/dt capability
- Application oriented characterization
- 100% avalanche tested

Description

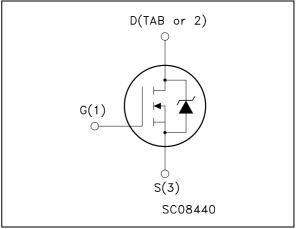
This Power MOSFET is the latest development of STMicroelectronics unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

Applications

Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STD35NF06T4	D35NF06	DPAK	Tape & reel

Contents

1	Electrical ratings	3
2	Electrical characteristics	4
	2.1 Electrical characteristics (curves)	6
3	Test circuit	8
4	Package mechanical data	9
5	Packing mechanical data 1 ⁻	1
6	Revision history	2



1

Electrical ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage ($V_{GS} = 0$)	60	V
V _{DGR}	Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)	60	V
V _{GS}	Gate- source voltage	± 20	V
Ι _D	Drain current (continuous) at $T_C = 25^{\circ}C$	35	А
Ι _D	Drain current (continuous) at T _C = 100°C	24.5	A
I _{DM} ⁽¹⁾	Drain current (pulsed)	140	А
P _{tot}	Total dissipation at $T_C = 25^{\circ}C$	80	W
	Derating Factor	0.53	W/°C
dv/dt ⁽²⁾	Peak diode recovery avalanche energy	5	V/ns
T _{stg}	Storage temperature	-55 to 175	°C
Тj	Max. operating junction temperature		

1. Pulse width limited by safe operating area.

2. I_{SD} \$5A, di/dt \leq 00A/µs, V_{DD} =V(_{BR)DSS}, $T_j \leq T_{JMAX}$

Table 2. Thermal data

Rthj-case	Thermal resistance junction-case max	1.88	°C/W
Rthj-amb	Thermal resistance junction-to ambient max	100	°C/W
Τ _J	Maximum lead temperature for soldering purpose	275	°C

Table 3. Avalanche characteristics

Symbol	Parameter	Max value	Unit
I _{AR}	Avalanche Current, Repetitive Or Not- repetitive (pulse width limited by T _j max)	17.5	A
E _{AS}	Single pulse avalanche energy (starting $T_j = 25 \text{ °C}$, $I_D = I_{AR}$, $V_{DD} = 50 \text{ V}$)	130	mJ



2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 250μΑ, V _{GS} =0	60			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V_{DS} = Max rating V_{DS} = Max rating, T_{C} = 125°C			1 10	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	$V_{GS} = \pm 20V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2	3	4	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10V, I _D = 17.5A		0.018	0.020	Ω

Table 4. On/off states

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g_{fs} ⁽¹⁾	Forward transconductance	$V_{DS} > I_{D(on)} x$ $R_{DS(on)max}, I_D = 17.5A$		13		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25V, f = 1MHz, V _{GS} = 0		1300 300 105		pF pF pF
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 30V, I_D = 27.5A$ $R_G = 4.7\Omega V_{GS} = 10V$ (see <i>Figure 12</i>)		20 50 36 15		ns ns ns ns
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 48V, I_D = 55A,$ $V_{GS} = 10V, R_G = 4.7\Omega$ (see <i>Figure 13</i>)		44.5 10.5 17.5	60	nC nC nC

1. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%.



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)				35 140	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 35A, V _{GS} = 0			1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 35A, di/dt = 100A/\mu s,$ $V_{DD} = 20V, T_j = 150^{\circ}C$ (see <i>Figure 14</i>)		75 170 4.5		ns μC Α

Table 6.Source drain diode

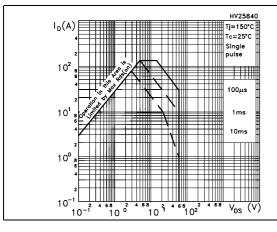
1. Pulse width limited by safe operating area.

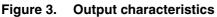
2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%



2.1 Electrical characteristics (curves)

Figure 1. Safe operating area





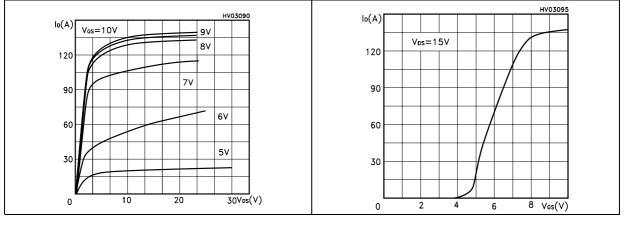
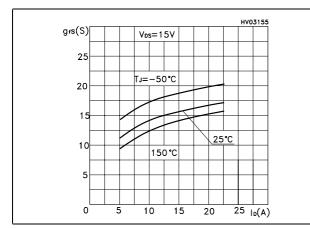
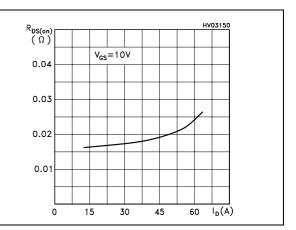


Figure 2.



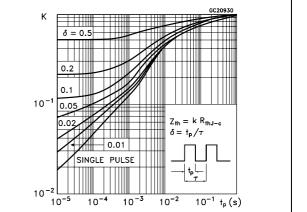






57





Thermal impedance

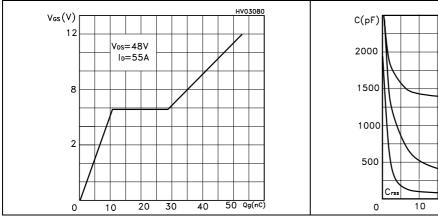


Figure 7. Gate charge vs. gate-source voltage Figure 8. Capacitance variations

Figure 9. Normalized gate threshold voltage vs. temperature

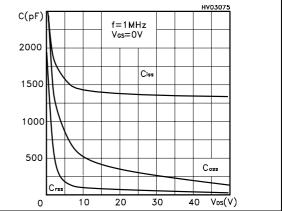


Figure 10. Normalized on resistance vs. temperature

0

-50

0

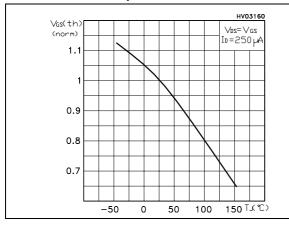
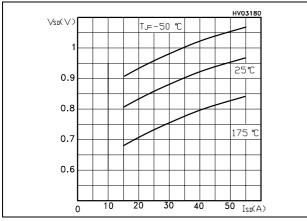
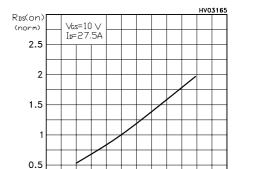


Figure 11. Source-drain diode forward characteristics







50

150 T√℃)

100

3 Test circuit

Figure 12. Switching times test circuit for resistive load

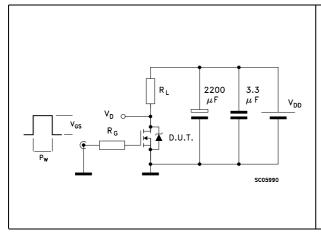
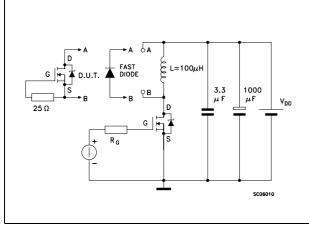


Figure 14. Test circuit for inductive load switching and diode recovery times





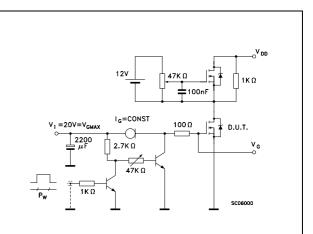


Figure 13. Gate charge test circuit

Figure 15. Unclamped Inductive load test circuit

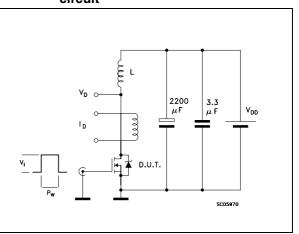
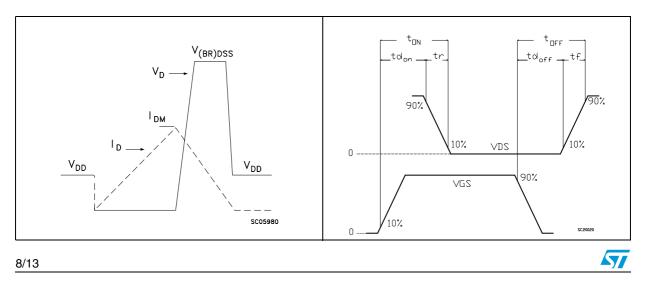


Figure 17. Switching time waveform



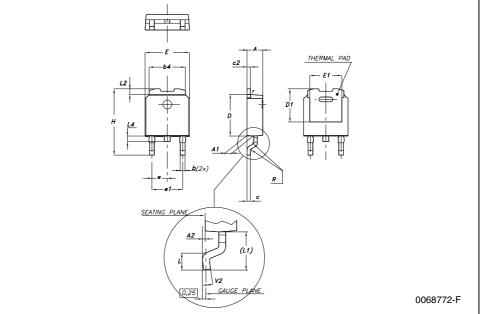
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



DIM.		mm.		inch		
DINI.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.9	0.025		0.035
b4	5.2		5.4	0.204		0.212
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
D1		5.1			0.200	
E	6.4		6.6	0.252		0.260
E1		4.7			0.185	
е		2.28			0.090	
e1	4.4		4.6	0.173		0.181
Н	9.35		10.1	0.368		0.397
L	1			0.039		
(L1)		2.8			0.110	
L2		0.8			0.031	
L4	0.6		1	0.023		0.039
R		0.2			0.008	
V2	0°		8°	0°		8°

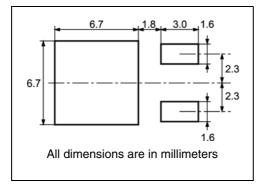


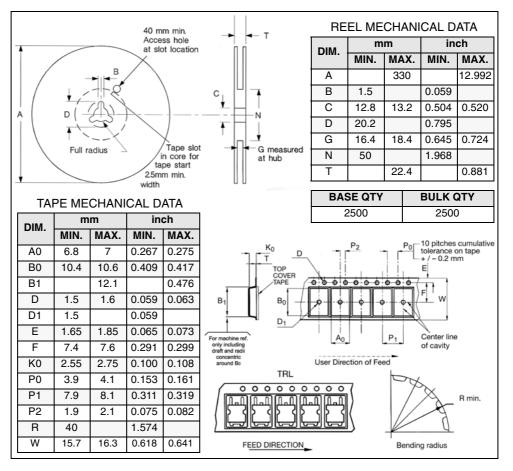




5 Packing mechanical data

DPAK FOOTPRINT





TAPE AND REEL SHIPMENT

57

6 Revision history

Date	Revision	Changes
21-Jun-2004	2	Preliminary version
06-Jul-2006	3	New template, no content change
20-Feb-2007	4	Typo mistake on page 1



Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZE REPRESENTATIVE OF ST, ST PRODUCTS ARE NOT DESIGNED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS, WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2007 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan -Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

